

ABSTRACT OF THE DISCLOSURE

A method and apparatus for performing a built-in self-test (“BIST”) on an integrated circuit device are disclosed. More particularly, in a first aspect, a dual mode BIST controller comprises both a logic built-in self-test (“LBIST”) domain and a memory built-in self-test (“MBIST”) domain. The LBIST domain includes a LBIST engine capable of executing a LBIST and storing the results thereof and a multiple input signature register (“MISR”). The MBIST domain includes a MBIST engine capable of executing a MBIST. In a second aspect, the invention includes a method for performing a BIST on an integrated circuit device. The method comprises externally resetting a dual mode BIST controller; performing at least one of a LBIST and a MBIST from the dual mode BIST controller; and obtaining the results of the performed BIST.

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